## IN THE CLAIMS

This listing of claims replaces all prior versions and listings of the claims in the above referenced application.

- 1. (Withdrawn) A light-emitting device comprising:
- a semiconductor structure including at least one p-type layer and one n-type layer, and
- a p contact and an n contact, the p contact electrically connected to the p-type layer, the n contact electrically connected to the n-type layer, wherein at least one of the p and n contacts is a multi-layered contact external to the semiconductor structure, the multi-layered contact comprising:
  - a metallic reflector layer;
  - a continuous uniform conducting sheet adjacent to the semiconductor structure, wherein the continuous uniform conducting sheet comprises a metal and makes ohmic contact to the structure; and
  - a conductive barrier layer interposing the reflector layer and the continuous uniform conducting sheet;

wherein the multi-layer contact has a reflectivity greater than 75% for light at an operating wavelength of the light-emitting device.

- 2. (Canceled).
- 3. (Withdrawn) A device, as defined in claim 1, wherein the multi-layer contact has a specific contact resistance less than  $10^{-2} \Omega$ -cm<sup>2</sup>.
  - (Canceled).
- 5. (Withdrawn) A device, as defined in claim 1, wherein the reflector layer has a thickness greater than 500 Å.
- 6. (Withdrawn) A device, as defined in claim 1, wherein the continuous uniform conducting sheet has a thickness less than 200 Å.

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- 7. (Withdrawn) A device, as defined in claim 1, wherein the reflector layer is selected from the group consisting of Al, Cu, Rh, Pd, and Au.
- 8. (Withdrawn) A device, as defined in claim 1, wherein the p and n contacts are on opposing faces of the semiconductor structure.
- 9. (Withdrawn) A device, as defined in claim 8, wherein the continuous uniform conducting sheet comprises Ni and Ag.
- 10. (Withdrawn) A device, as defined in claim 8, wherein the reflector layer comprises Ag.
- 11. (Currently Amended) A light-emitting semiconductor device comprising:

  a semiconductor structure having at least one p-type and one n-type layer, and

  a p contact and an n contact, the p contact electrically connected to the p-type layer,
  the n contact electrically connected to the n-type layer, wherein at least one of the p and n

  contacts is a multi-layer contact external to the semiconductor structure, the multi-layer

  contact comprising:

a metallic reflector layer comprising Ag; and

a continuous uniform conducting sheet adjacent to the semiconductor structure, wherein the continuous uniform conducting sheet comprises Ni and makes ohmic contact to the structure;

wherein the multi-layer contact has a reflectivity greater than 75% for light at an operating wavelength of the light-emitting device and a specific contact resistance less than  $10^{-2} \Omega$ -cm<sup>2</sup>.

- 12-13. (Canceled).
- 14. (Previously Presented) A device, as defined in claim 11, the multi-layer contact further comprising a barrier layer interposing the reflector layer and the continuous uniform conducting sheet.
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- 15. (Original) A device, as defined in claim 11, the reflector layer having a thickness greater than 500 Å.
- 16. (Previously Presented) A device, as defined in claim 11, wherein the continuous uniform conducting sheet has a thickness less than 200 Å.
  - 17. (Canceled).
- 18. (Previously Presented) A device, as defined in claim 11, wherein the continuous uniform conducting sheet is selected from the group that consists of Au/NiO and Ni/Au.
- 19. (Withdrawn) A device, as defined in claim 1, wherein the semiconductor structure includes at least one III-nitride layer.
- 20. (Previously Presented) A device, as defined in claim 11, wherein the semiconductor structure includes at least one III-nitride layer.
- 21. (Withdrawn) A device, as defined in claim 1, wherein the continuous uniform conducting sheet absorbs less than 25% of light generated in the semiconductor structure and incident on the continuous uniform conducting sheet.
- 22. (Withdrawn) A device, as defined in claim 19, wherein a voltage required to forward bias the device is less than 3.5 V.
- 23. (Withdrawn) A device, as defined in claim 1, wherein the continuous uniform conducting sheet has thickness less than 100 Å.
  - 24. (Withdrawn) A device, as defined in claim 1, wherein:

the continuous uniform conducting sheet comprises Au and has a thickness less than 35 Å;

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the conductive barrier layer comprises Rh and has a thickness less than 50 Å; and the metallic reflector layer comprises Al.

- 25. (Withdrawn) A device, as defined in claim 8, wherein at least a portion of the n contact overlies at least a portion of the p contact.
  - 26. (Canceled).
  - 27. (Canceled).
- 28. (Previously Presented) A device, as defined in claim 11, wherein the continuous uniform conducting sheet absorbs less than 25% of light generated in the semiconductor structure and incident on the continuous uniform conducting sheet.
- 29. (Previously Presented) A device, as defined in claim 20, wherein a voltage required to forward bias the device is less than 3.5 V.
- 30. (Previously Presented) A device, as defined in claim 11, wherein the continuous uniform conducting sheet has thickness less than 100 Å.
- 31. (Currently Amended) A light-emitting semiconductor device comprising:
  a semiconductor structure having at least one p-type and one n-type layer, and
  a p contact and an n contact, the p contact electrically connected to the p-type layer,
  the n contact electrically connected to the n-type layer, wherein at least one of the p and n
  contacts is a multi-layer contact external to the semiconductor structure, the multi-layer
  contact comprising:
  - a metallic reflector comprising Al; and
  - a continuous uniform conducting sheet adjacent to the semiconductor structure, wherein the continuous uniform conducting sheet comprises Ni and makes ohmic contact to the structure;

wherein the multi-layer contact has a reflectivity greater than 75% for light at an operating wavelength of the light-emitting device and a specific contact resistance less than  $10^{-2} \Omega$ -cm<sup>2</sup>.

32-34. (Canceled).

FAYEVT LAW GROUP 119 2645 N. FIRST ST. SINTR 223 SAN JOSE, CA. 65154 (409) 182-0481 FAX (408) 182-0481 35. (Previously Presented) A device, as defined in claim 31, wherein: the continuous uniform conducting sheet comprises Au.

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